



April 2008

## FDMA1025P

### Dual P-Channel PowerTrench® MOSFET

-20V, -3.1A, 155mΩ

#### Features

- Max  $r_{DS(on)}$  = 155mΩ at  $V_{GS} = -4.5V$ ,  $I_D = -3.1A$
- Max  $r_{DS(on)}$  = 220mΩ at  $V_{GS} = -2.5V$ ,  $I_D = -2.3A$
- Low profile - 0.8mm maximum - in the new package MicroFET 2X2 mm
- RoHS Compliant



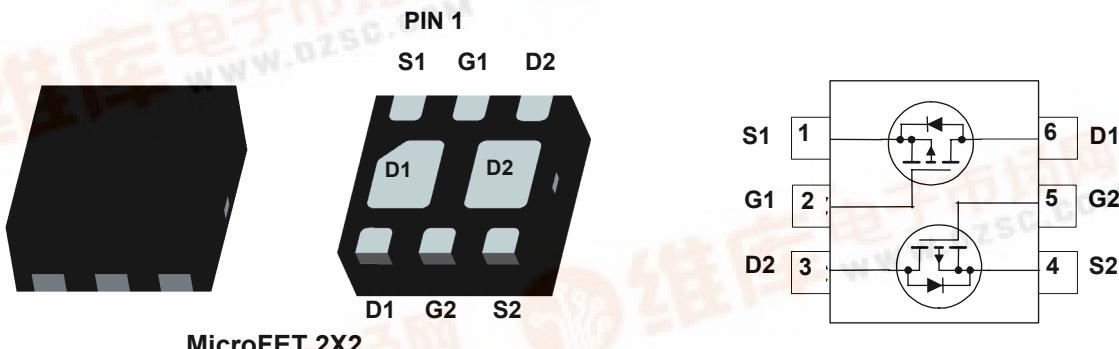
#### General Description

This device is designed specifically as a single package solution for the battery charge switch in cellular handset and other ultra-portable applications. It features two independent P-Channel MOSFETs with low on-state resistance for minimum conduction losses. When connected in the typical common source configuration, bi-directional current flow is possible.

The MicroFET 2X2 package offers exceptional thermal performance for its physical size and well suited to linear mode applications.

#### Application

- DC - DC Conversion



#### MOSFET Maximum Ratings $T_A = 25^\circ C$ unless otherwise noted

Symbol	Parameter	Ratings	Units
$V_{DS}$	Drain to Source Voltage	-20	V
$V_{GS}$	Gate to Source Voltage	$\pm 12$	V
$I_D$	Drain Current -Continuous	(Note 1a)	-3.1
	-Pulsed		-6
$P_D$	Power Dissipation for Single Operation	(Note 1a)	1.4
	Power Dissipation	(Note 1b)	0.7
$T_J, T_{STG}$	Operating and Storage Junction Temperature Range	-55 to +150	°C

#### Thermal Characteristics

$R_{QJA}$	Thermal Resistance Single Operation, Junction to Ambient	(Note 1a)	86	°C/W
$R_{QJA}$	Thermal Resistance Single Operation, Junction to Ambient	(Note 1b)	173	
$R_{QJA}$	Thermal Resistance Dual Operation, Junction to Ambient		69	
$R_{QJA}$	Thermal Resistance Dual Operation, Junction to Ambient		151	

#### Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
025	FDMA1025P	MicroFET 2X2	7"	8mm	3000 units

**Electrical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
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**Off Characteristics**

$\text{BV}_{\text{DSS}}$	Drain to Source Breakdown Voltage	$I_D = -250\mu\text{A}, V_{GS} = 0\text{V}$	-20			V
$\frac{\Delta \text{BV}_{\text{DSS}}}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$ , referenced to $25^\circ\text{C}$		14		$\text{mV/}^\circ\text{C}$
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS} = -16\text{V}, V_{GS} = 0\text{V}$			-1	$\mu\text{A}$
$I_{\text{GSS}}$	Gate to Source Leakage Current	$V_{GS} = \pm 12\text{V}, V_{DS} = 0\text{V}$			-100	nA

**On Characteristics**

$V_{GS(\text{th})}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = -250\mu\text{A}$	-0.4	-0.9	-1.5	V
$\frac{\Delta V_{GS(\text{th})}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = -250\mu\text{A}$ , referenced to $25^\circ\text{C}$		-3.8		$\text{mV/}^\circ\text{C}$
$r_{DS(\text{on})}$	Drain to Source On Resistance	$V_{GS} = -4.5\text{V}, I_D = -3.1\text{A}$		88	155	$\text{m}\Omega$
		$V_{GS} = -2.5\text{V}, I_D = -2.3\text{A}$		144	220	
		$V_{GS} = -4.5\text{V}, I_D = -3.1\text{A}, T_J = 125^\circ\text{C}$		121	220	
$g_{\text{FS}}$	Forward Transconductance	$V_{DS} = -5\text{V}, I_D = -3.1\text{A}$		6.2		S

**Dynamic Characteristics**

$C_{\text{iss}}$	Input Capacitance	$V_{DS} = -10\text{V}, V_{GS} = 0\text{V}, f = 1\text{MHz}$		340	450	pF
$C_{\text{oss}}$	Output Capacitance			80	105	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance			45	70	pF

**Switching Characteristics**

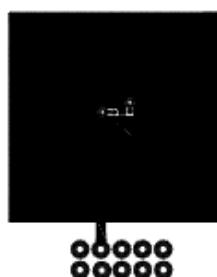
$t_{\text{d}(\text{on})}$	Turn-On Delay Time	$V_{DD} = -10\text{V}, I_D = -3.1\text{A}$		5	10	ns
$t_r$	Rise Time	$V_{GS} = -4.5\text{V}, R_{\text{GEN}} = 6\Omega$		14	26	ns
$t_{\text{d}(\text{off})}$	Turn-Off Delay Time			13	24	ns
$t_f$	Fall Time			8	16	ns
$Q_{\text{g}(\text{TOT})}$	Total Gate Charge at 4.5V	$V_{GS} = 0\text{V} \text{ to } -4.5\text{V}$	$V_{DD} = -10\text{V}$	3.4	4.8	nC
$Q_{\text{gs}}$	Gate to Source Gate Charge		$I_D = -3.1\text{A}$	0.8		nC
$Q_{\text{gd}}$	Gate to Drain "Miller" Charge			1.0		nC

**Drain-Source Diode Characteristics**

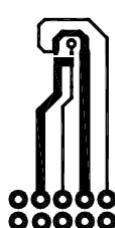
$V_{\text{SD}}$	Source to Drain Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = -1.1\text{A}$ (Note 2)		-0.8	-1.2	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_F = -3.1\text{A}, di/dt = 100\text{A}/\mu\text{s}$		17	26	ns
$Q_{\text{rr}}$	Reverse Recovery Charge			10	15	nC

**Notes:**

1.  $R_{\text{QJA}}$  is determined with the device mounted on a  $1\text{in}^2$  pad 2 oz copper pad on a  $1.5 \times 1.5$  in. board of FR-4 material.  $R_{\text{QJC}}$  is guaranteed by design while  $R_{\text{QCA}}$  is determined by the user's board design.



a.  $86^\circ\text{C}/\text{W}$  when mounted on a  $1\text{in}^2$  pad of 2 oz copper.



b.  $173^\circ\text{C}/\text{W}$  when mounted on a minimum pad.

2. Pulse Test: Pulse Width  $< 300\mu\text{s}$ , Duty cycle  $< 2.0\%$ .

**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted

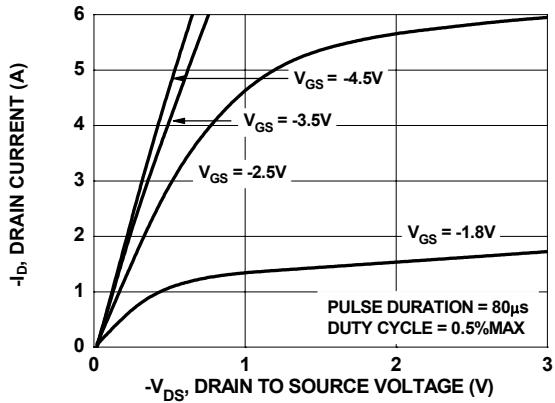


Figure 1. On Region Characteristics

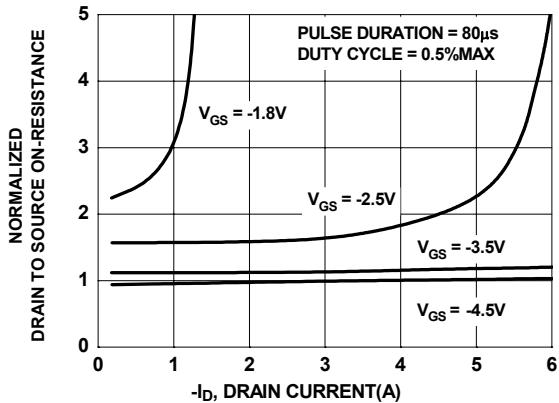


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

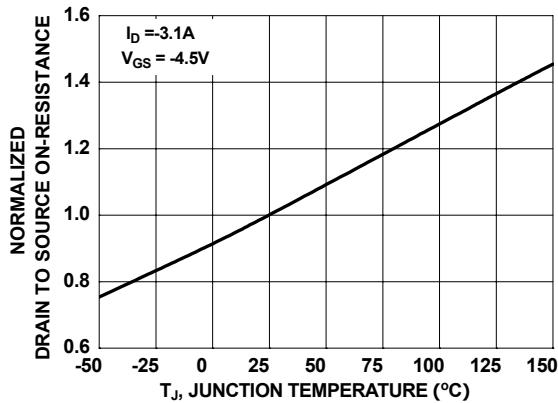


Figure 3. Normalized On Resistance vs Junction Temperature

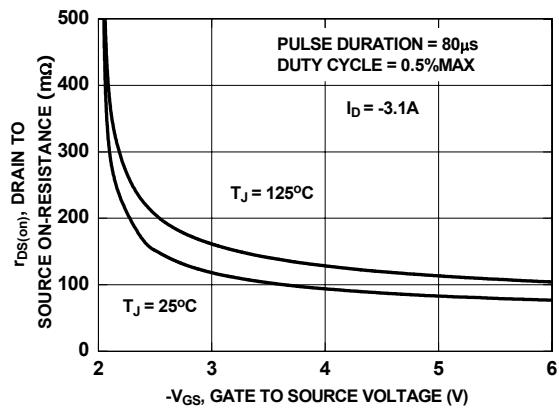


Figure 4. On-Resistance vs Gate to Source Voltage

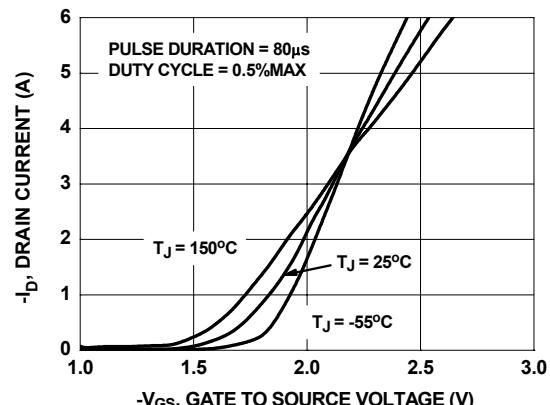


Figure 5. Transfer Characteristics

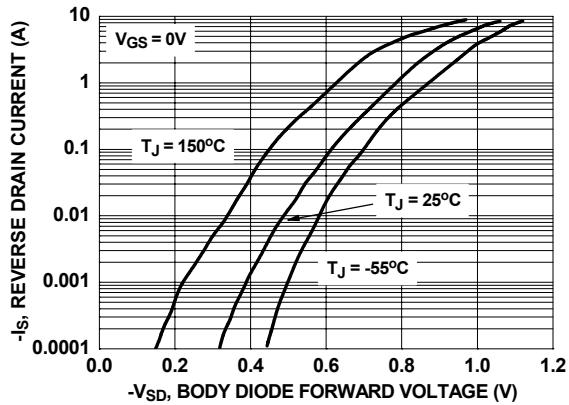


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

**Typical Characteristics**  $T_J = 25^\circ\text{C}$  unless otherwise noted

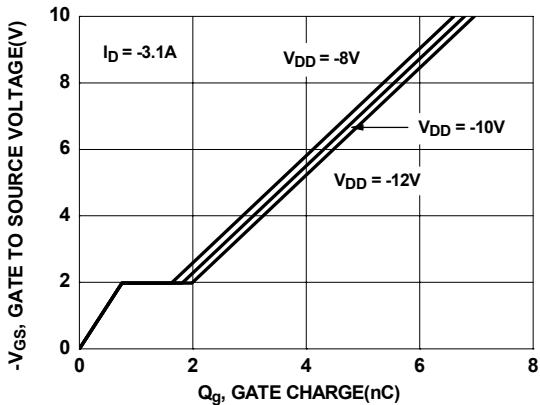


Figure 7. Gate Charge Characteristics

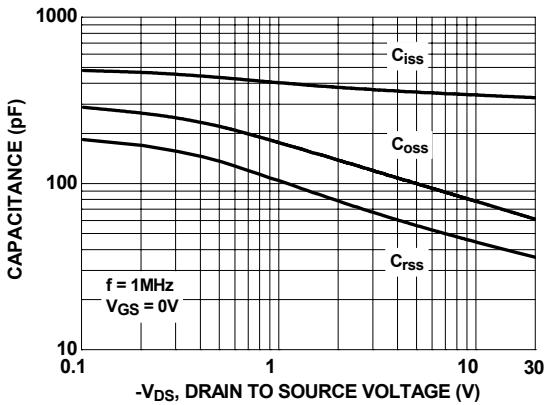


Figure 8. Capacitance vs Drain to Source Voltage

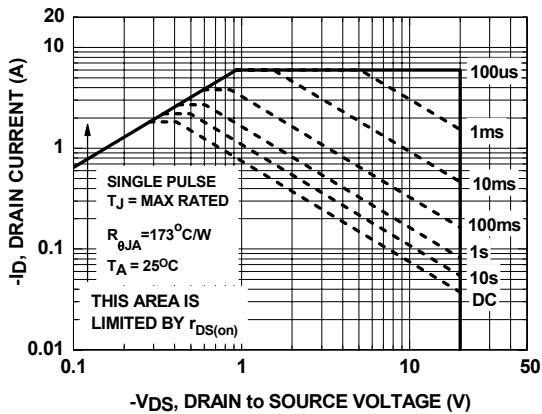


Figure 9. Forward Bias Safe Operating Area

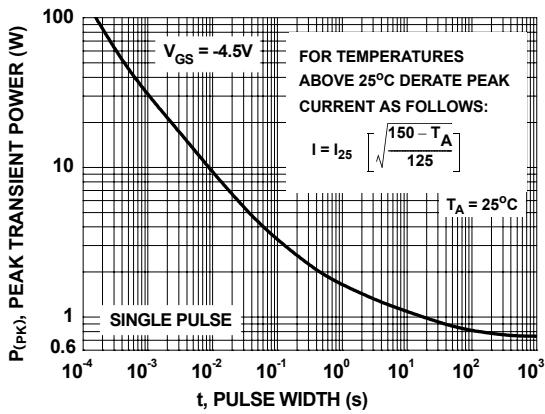


Figure 10. Single Pulse Maximum Power Dissipation

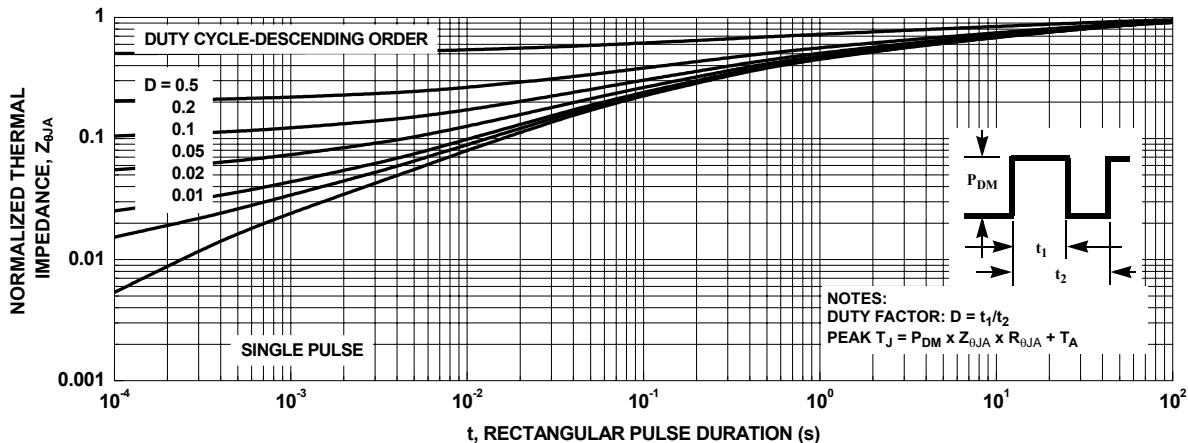
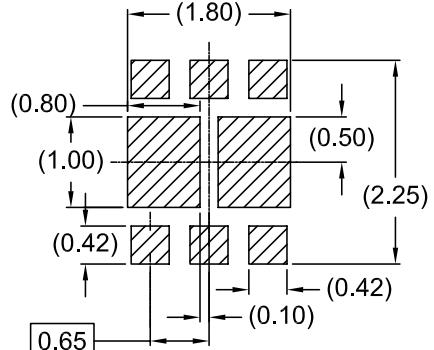
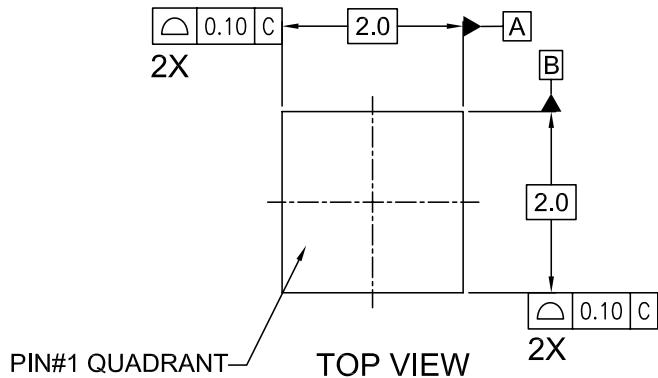
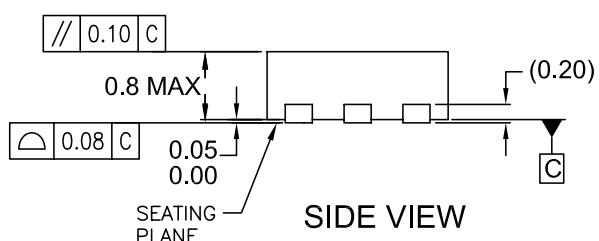


Figure 11. Transient Thermal Response Curve

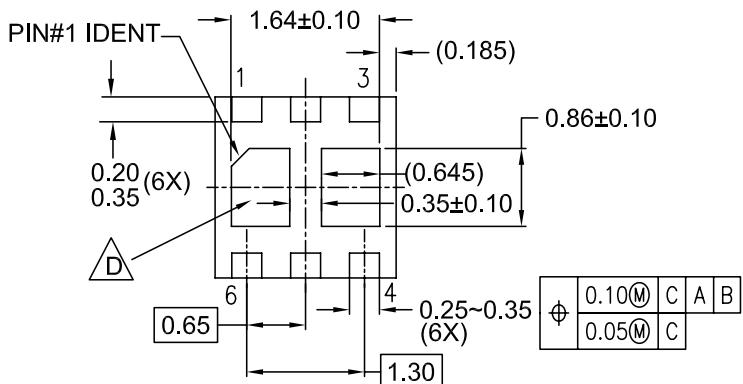
## Dimensional Outline and Pad Layout



## RECOMMENDED LAND PATTERN



### SIDE VIEW



## BOTTOM VIEW

## NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229,  
VARIATION VCCC EXCEPT AS NOTED.
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER  
ASME Y14.5M, 1994
-  D. NON-JEDEC DUAL DAP
- E. DRAWING FILE NAME :  
MLP06Jrev3



## D. NON-JEDEC DUAL DAP



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Rev. I34